HN7G05FU

TOSHIBA Multichip Discrete Device

HN7G05FU

Power Management Switch Applications, Inverter Circuit Applications, Driver Circuit Applications and Interface Circuit Applications

Q1 (transistor): RN2301 equivalent Q2 (MOSFET): 2SK1830 equivalent

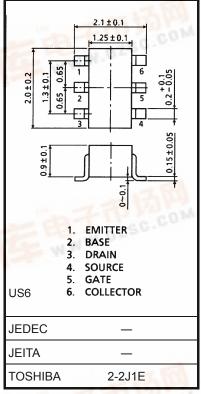
Q1 (Transistor) Absolute Maximum Ratings $(Ta = 25^{\circ}C)$

Characteristic	Symbol	Rating	Unit
Collector-base voltage	V _{CBO}	-50	V
Collector-emitter voltage	V _{CEO}	-50	V
Emitter-base voltage	V _{EBO}	-10	V
Collector current	- Ic	-100	mA

Q2 (MOSFET) Absolute Maximum Ratings (Ta = 25°C)

Characteristic	Symbol	Rating	Unit
Drain-source voltage	V _{DS}	20	V
Gate-source voltage	V _{GSS}	10	V
Drain current	ID	50	mA

Unit: mm



Weight: 0.0068 g (typ.)

Marking

Q1, Q2 Common Ratings (Ta = 25°C)

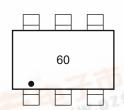
Characteristic	Symbol	Rating	Unit
Power dissipation	P (Note 1)	200	mW
Junction temperature	Tj	150	°C
Storage temperature range	T _{stg}	−55~150	°C

Note: Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings.

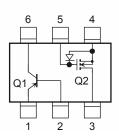
> Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling

reliability data (i.e. reliability test report and estimated failure rate, etc).

Precautions"/"Derating Concept and Methods") and individual



Equivalent Circuit (top view)



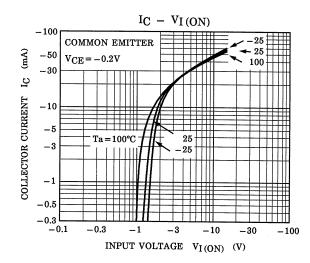
Q1 (Transistor) Electrical Characteristics (Ta = 25°C)

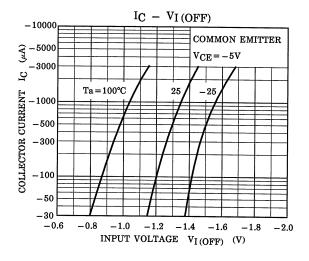
Characteristic	Symbol	Test Condition	Min	Тур.	Max	Unit
Collector cutoff current	I _{CBO}	$V_{CB} = -50 \text{ V}, I_E = 0$	_	_	-100	nA
	I _{CEO}	$V_{CE} = -50 \text{ V}, I_{E} = 0$			-500	nA
Emitter cutoff current	I _{EBO}	$V_{EB} = -5 \text{ V}, I_C = 0$	-0.82	_	-1.52	mA
DC current gain	h _{FE}	$V_{CE} = -5 \text{ V}, I_{C} = -10 \text{ mA}$	30	_		
Collector-emitter saturation voltage	V _{CE (sat)}	$I_C = -5 \text{ mA}, I_B = -0.25 \text{ mA}$	_	-0.1	-0.3	V
Input voltage (ON)	$V_{I(ON)}$	$V_{CE} = -0.2 \text{ V}, I_{C} = -5 \text{ mA}$	-1.1	_	-2.0	V
Input voltage (OFF)	V _{I(OFF)}	$V_{CE} = -5 \text{ V}, I_{C} = -0.1 \text{ mA}$	-1.0	_	-1.5	V
Input resistor	R1	_	3.29	4.7	6.11	kΩ
Resistor ratio	R1/R2	_	0.9	1.0	1.1	

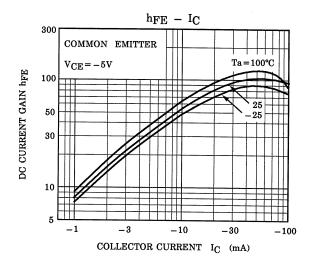
Q2 (MOSFET) Electrical Characteristics (Ta = 25°C)

Characteristic	Symbol	Test Condition	Min	Тур.	Max	Unit
Gate leakage current	I _{GSS}	V _{GS} = 10 V, V _{DS} = 0	_	_	1	μА
Drain-source breakdown voltage	V (BR) DSS	$I_D = 100 \mu A, V_{GS} = 0$	20	_	_	V
Drain cutoff current	I _{DSS}	$V_{DS} = 20 \text{ V}, V_{GS} = 0$			1	μΑ
Gate threshold voltage	V _{th}	$V_{DS} = 3 \text{ V}, I_D = 0.1 \text{ mA}$	0.5		1.5	٧
Forward transfer admittance	Y _{fs}	$V_{DS} = 3 \text{ V}, I_D = 10 \text{ mA}$	20		_	mS
Drain-source ON-resistance	R _{DS} (ON)	I_D = 10 mA V_{GS} = 2.5 V	_	20	40	Ω

Q1 (Transistor)

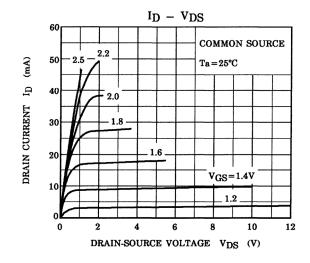


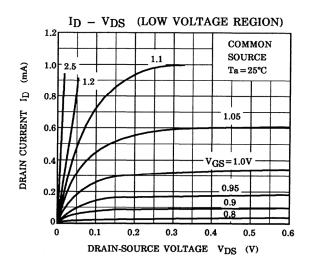


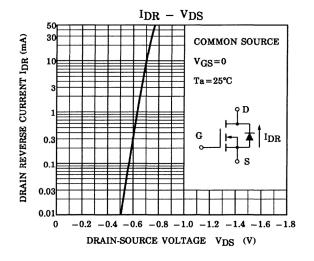


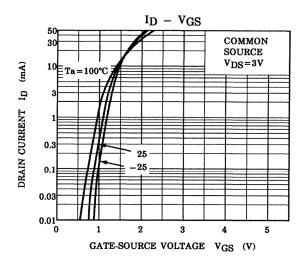
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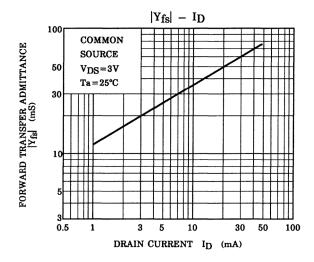
Q2 (S-MOS)

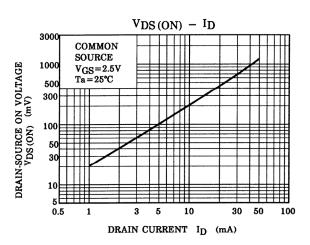




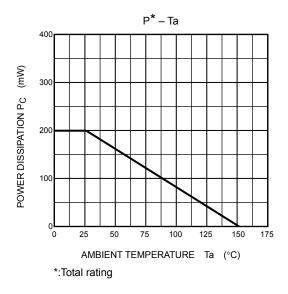








Q1, Q2 common



5

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